**Workshop on novel developments and detectors for nano-imaging and nano-analysis**

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The workshop is organized as part of the [fit4nano COST action](https://fit4nano.eu/) [1], WG1-Tool Development, dedicated to novel instrumentation and methodologies developments for nano-imaging and nano-analysis.

While this workshop will cover all aspects of instrument development related to focused ion beams, a major focus will be on advanced charged particle detectors with better sensitivity, higher spatial resolution, higher dynamic range, longer lifetime, lower cost, etc., for advanced nano-analytical instruments.

The workshop will take place on 09th -10th October 2023 in Belval, Luxembourg

The maximum length of the abstract is two pages, including figures and references, in either Word or pdf format. The abstract should be submitted by email to [hung.hoang@list.lu](mailto:hung.hoang@list.lu) by Friday, 08th September 2023

**Reference**

[1] www.fit4nano.eu/